

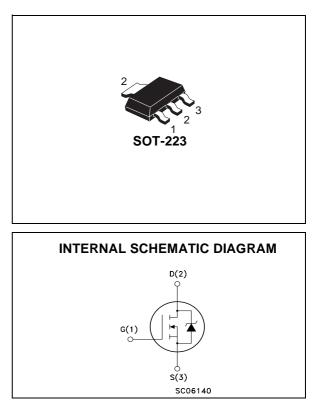
N-CHANNEL 100V - 0.055 Ω - 5A SOT-223 LOW GATE CHARGE STripFET™ II POWER MOSFET

ТҮРЕ	V _{DSS}	R _{DS(on)}	I _D
STN7NF10	100 V	< 0.065 Ω	5 A

- TYPICAL $R_{DS}(on) = 0.055 \Omega$
- APPLICATION ORIENTED CHARACTERIZATION

DESCRIPTION

This Power MOSFET series realized with STMicroelectronics unique STripFET process has specifically been designed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced high-efficiency isolated DC-DC converters for Telecom and Computer application. It is also intended for any application with low gate charge drive requirements.



APPLICATIONS

- HIGH-EFFICIENCY DC-DC CONVERTERS
- UPS AND MOTOR CONTROL

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	100	V
V _{DGR}	Drain-gate Voltage (R_{GS} = 20 k Ω)	100	V
V _{GS}	Gate- source Voltage	±20	V
ID	Drain Current (continuous) at $T_C = 25^{\circ}C$	5	А
I _D	Drain Current (continuous) at T _C = 100°C	3.4	A
I _{DM} (•)	Drain Current (pulsed)	20	A
P _{TOT}	Total Dissipation at T _C = 25°C	3.3	W
	Derating Factor	0.026	W/°C
T _{stg}	Storage Temperature	-55 to 150	°C
Тj	Operating Junction Temperature	-35 10 150	

(•) Pulse width limited by safe operating area

STN7NF10

THERMAL DATA

Rthj-PCB	Thermal Resistance Junction-PCB Max(*)	38	°C/W
Rthj-PCB	Thermal Resistance Junction-PCB Max(**)	100	°C/W
ΤI	Maximum Lead Temperature For Soldering Purpose (1.6 mm from case,for 10s)	260	°C

Note: (*) When mounted on 1 in² FR-4 BOARD,2 oz Cu, t<10s.

Note: (**) When mounted on minimum footprint.

ELECTRICAL CHARACTERISTICS (T_{CASE} = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0	100			V
I _{DSS}	Zero Gate Voltage	V _{DS} = Max Rating			1	μA
	Drain Current (V _{GS} = 0)	V_{DS} = Max Rating, T_{C} = 125 °C			10	μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA

ON (1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10V, I _D = 1.5 A		0.055	0.065	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (1)	Forward Transconductance	$V_{DS} = 15 \text{ V}$, $I_{D} = 1.5 \text{ A}$		12		S
Ciss	Input Capacitance	$V_{DS} = 25 \text{ V}, \text{ f} = 1 \text{ MHz}, V_{GS} = 0$		870		pF
Coss	Output Capacitance			125		pF
C _{rss}	Reverse Transfer Capacitance			52		pF

ELECTRICAL CHARACTERISTICS (CONTINUED) SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on Delay Time	$V_{DD} = 50 \text{ V}, I_D = 12 \text{ A}$		58		ns
t _r	Rise Time	$\label{eq:RG} \begin{split} R_{G} &= 4.7\Omega \; V_{GS} = 10 \; V \\ (\text{see test circuit, Figure 3}) \end{split}$		45		ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 80 V, I _D = 24 A, V _{GS} = 10 V		30 6 10	41	nC nC nC

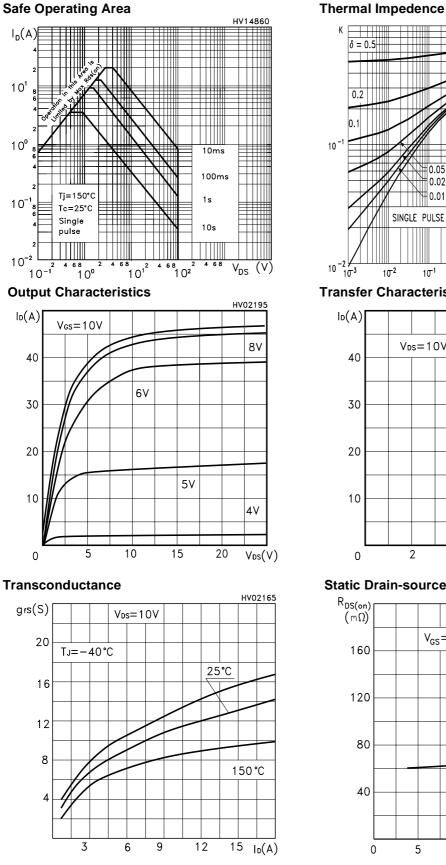
SWITCHING OFF

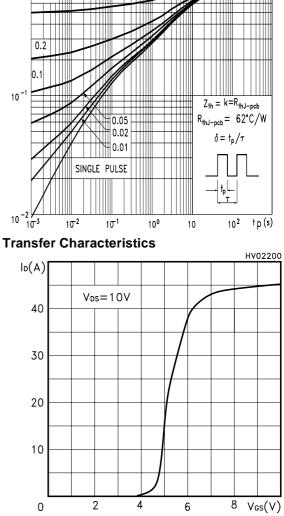
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)}	Turn-off-Delay Time	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 12 \text{ A},$		49		ns
t _f	Fall Time	$R_G = 4.7\Omega$, $V_{GS} = 10V$		17		ns
		(see test circuit, Figure 3)				

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain Current				5	А
I _{SDM} (1)	Source-drain Current (pulsed)				20	А
V _{SD} (2)	Forward On Voltage	$I_{SD} = 5 \text{ A}, V_{GS} = 0$			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 5 \text{ A}$, di/dt = 100A/µs, V _{DD} = 30 V, T _j = 150°C (see test circuit, Figure 5)		100 375 7.5		ns nC A

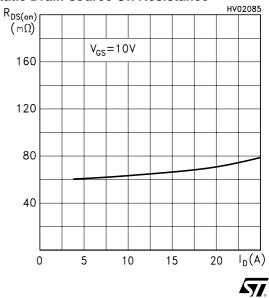
Note: 1. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.
2. Pulse width limited by safe operating area.

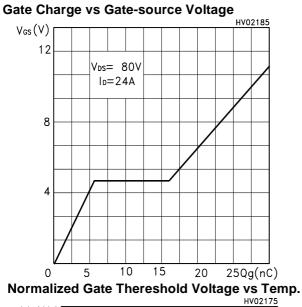


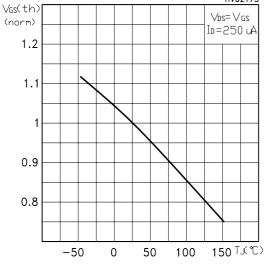


SUL-35.

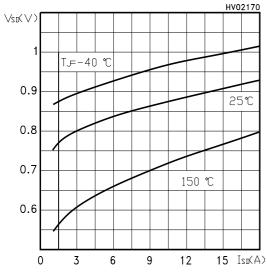
Static Drain-source On Resistance

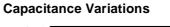


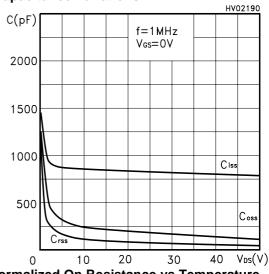




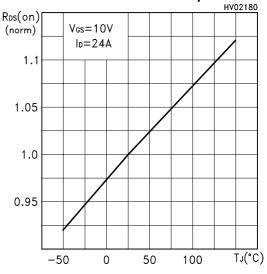












STN7NF10

Fig. 1: Unclamped Inductive Load Test Circuit

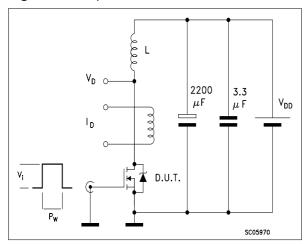


Fig. 3: Switching Times Test Circuit For Resistive Load

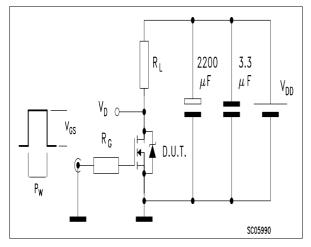


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

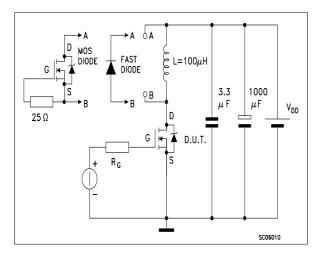


Fig. 2: Unclamped Inductive Waveform

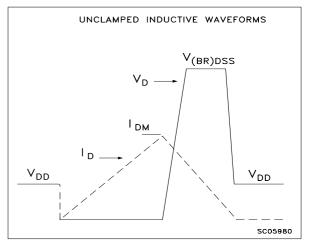
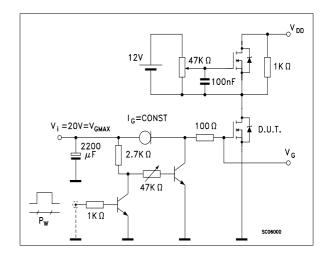
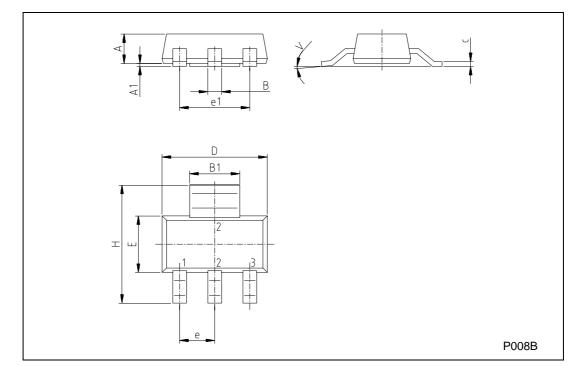


Fig. 4: Gate Charge test Circuit



DIM.		mm		inch			
Dim.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А			1.80			0.071	
В	0.60	0.70	0.80	0.024	0.027	0.031	
B1	2.90	3.00	3.10	0.114	0.118	0.122	
С	0.24	0.26	0.32	0.009	0.010	0.013	
D	6.30	6.50	6.70	0.248	0.256	0.264	
е		2.30			0.090		
e1		4.60			0.181		
E	3.30	3.50	3.70	0.130	0.138	0.146	
н	6.70	7.00	7.30	0.264	0.276	0.287	
V			10 ⁰			10 [°]	
A1		0.02					

SOT-223 MECHANICAL DATA



Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics. © The ST logo is a registered trademark of STMicroelectronics

© 2002 STMicroelectronics - Printed in Italy - All Rights Reserved STMicroelectronics GROUP OF COMPANIES Australia - Brazil - Canada - China - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco Singapore - Spain - Sweden - Switzerland - United Kingdom - United States. © http://www.st.com